Opening Remarks
Seiji Kajihara, Dean of School of Computer Science and Systems Engineering, Kyushu Institute of Technology, Japan

Introduction to DISC
Hiroshi Ochi, Professor and Director of DISC, Kyushu Institute of Technology, Japan

Keynote/Tutorial
- Has Fault Model Based Structural Test Hit a Brick Wall? Are In-System Tests Unavoidable?
  Adit Singh, James B. Davis Professor, Dept. of Electrical and Computer Engineering, Auburn University, USA

Break

Invited Talk
- Interval Property Checking for Hardware Design Using Satisfiability Modulo Theories Solver
  Nguyen Duc Minh, Professor, School of Electronics and Telecommunications, Hanoi University of Science and Technology, Vietnam

Lunch

DISC Research Presentation I (LSI Design)
Chair: Leonardo Lanante, Assistant Professor, DISC, Kyushu Institute of Technology, Japan

1. On Avoiding Test Data Corruption by Optimal Scan Chain Grouping
   Y. Zhang, S. Holst, X. Wen, K. Miyase, S. Kajihara, and J. Qian

2. A Multimode FFT Improvement for IEEE 802.11 ax WLAN Devices
   P. T.K. Dinh, L.T. Dinh, H. V. Tran, C.M. Duong, L. Lanante Jr, M. Kurosaki, M. D. Nguyen, and H. Ochi

3. Study of Neural Networks Implementation in FPGA using SW/HW Co-design
   N. b. Ismail, Y. Igarashi, M. Kurosaki, L. Lanante Jr, and H. Ochi

4. World’s First Industrial Wireless LAN with Low Latency, High Reliability and Highly Safe

Break

DISC Research Presentation II (LSI Test)
Chair: Kohei Miyase, Associate Professor, DISC, Kyushu Institute of Technology, Japan

5. Fully Digital Ternary Content Addressable Memory using Ratio-less SRAM Cells and Hierarchical-AND Matching Comparator for Ultra-low-voltage Operation

6. Locating Hotspots with Justification Techniques in a Layout Design
   Y. Kawano, K. Miyase, X. Wen, and S. Kajihara

7. Flip-Flop Selection for Multi-Cycle Test with Partial Observation in Scan-Based Logic BIST
   S. Oshima, T. Kato, S. Wang, Y. Sato, and S. Kajihara

8. Good Die Prediction Modeling from Specific Results of Wafer Tests
   T. Nishimi, S. Kajihara, and Y. Nakamura

Break

Closing Remarks
Kazuyuki Nakamura, Professor, Center for Microelectronic System, Kyushu Institute of Technology, Japan

All presentation files can be downloaded from 2018/1/19 through the following link:
https://www.dropbox.com/s/mqs33fpq2b5zpbs/DISC-2018_Presentation_Files.zip?dl=0